## Notice of References Cited Application/Control No. 10/810,660 Examiner Jarrett J. Stark Applicant(s)/Patent Under Reexamination LIN, WEN-JIAN Page 1 of \$\frac{1}{2}\$

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-7,016,099 B2	03-2006	Ikeda et al.	359/291
*	В	US-2005/0085000	04-2005	Ikeda et al.	438/053
*	С	US-2004/0077119 A1	04-2004	Ikeda et al.	438/052
*	D	US-2004/0076008 A1	04-2004	Ikeda, Koichi	362/259
*	Е	US-2004/0004592 A1	01-2004	Ikeda et al.	345/85
*	F	US-2003/0035197 A1	02-2003	Ikeda et al.	359/295
*	G	US-6,946,315 B2	09-2005	Ikeda et al.	438/52
*	Н	US-6,838,304 B2	01-2005	lkeda et al.	438/52
*	1	US-6,760,146 B2	07-2004	Ikeda et al.	359/291
*	J	US-7,116,462 B2	10-2006	Ikeda, Koichi	359/291
*	К	US-7,102,808 B2	09-2006	Kasai, Hiroto	359/290
*	L	US-5,500,761 A	03-1996	Goossen et al.	359/290
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	Ν		•			
	0					
	Р					
	α					
	R					
	S					
	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	٧	
	w	
	x	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.